

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination TANIKAWA ET AL.	
		Examiner Philip B Tran	Art Unit 2155	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-6,157,953	12-2000	Chang et al.	709/225
B	US-5,965,860	10-1999	Oneda, Hideo	235/382
C	US-6,529,946	03-2003	Yokono et al.	709/217
D	US-2001/0037310	11-2001	Saeki, Tomoya	705/64
E	US-2001/0058468	12-2001	Okayasu et al.	713/168
F	US-2002/0095588	07-2002	Shigematsu et al.	713/186
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N	EP 1043648A2	11-2000	D	Stoltz et al	—
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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